

User Guide Lenovo UEFI Diagnostics for Think and Idea Version 03.06.000

Revision History

Revision	Date	Description of changes
1	April 18, 2016	Initial Version
2	June 03, 2016	Updated to version 3.5
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Summary	
Objective	6
Install and Run the UEFI diagnostics	6
Download the Bootable UEFI Diagnostics and Cre Drive Using Windows GUI	
Run the UEFI Diagnostics	6
Main Screen	
CPU Quick Test	
CPU Extended Test	
Fan Test	
Memory	
Memory quick test	23
Memory Extended Tests	
Motherboard Test	
PCI-e Test	
RAID Test	
Storage Test	
Optical Device Test	
Video Card test	
Run All Tests	
Log Screen	
Save Log Window	53
System Information	
Recover Bad Sectors Tool Screen	
Exit Application	74

Figure 1 - Application Main Screen	8
Figure 2 – CPU screen	. 11
Figure 3 – CPU quick test	. 12
Figure 4 - CPU quick test progress	. 13
Figure 5 - Select Algorithms Screen	. 17
Figure 6 - Window is displayed with instructions for user about current	
LCD test	. 18
Figure 7 - Screen painted with pattern of current LCD test	. 19
Figure 8 - Window asking user if screen was painted correctly	. 20
Figure 9 - Fan test screen	. 21
Figure 10 - Memory – Quick test Screen	. 23
Figure 11 - Memory extended test	. 26
Figure 12 - Memory extended test progress	. 27
Figure 13 - Select Algorithm Screen	. 29
Figure 14 - Motherboard test screen	. 30
Figure 15 - PCI Express test screen	. 32
Figure 16 - RAID test selecting device	. 35
Figure 17 - RAID selecting tests	. 36
Figure 18 - RAID test progress	. 37
Figure 19 - Select Devices Screen	. 39
Figure 20 - Select Devices Screen popup details	. 40
Figure 21 - Select Tests Screen	. 41
Figure 22 – Storage Test Screen	. 42
Figure 23 - Select Algorithm Screen	. 45
Figure 24 - Optical Device Test screen	. 46
Figure 25 – Run All test	. 49
Figure 26 – Run all test progress	. 50
Figure 27 - Log Screen for Quick Memory Test	. 52
Figure 28- Save Log Window	. 53
Figure 29 - Log saving operation was successful	. 55
Figure 30 - System Information Screen – System Tab	. 56
Figure 31 - System Information Screen – CPU Tab	. 57
Figure 32 - System Information Screen – Display Tab	. 58
Figure 33- System Information Screen – Memory Tab	. 59
Figure 34 - System Information Screen – Motherboard Tab	. 60
Figure 35 - System Information Screen – Optical Device Tab	. 61
Figure 36 - System Information Screen – PCI Express Tab	. 62
Figure 37 - System Information Screen – Storage Tab	. 63

Figure 38 - Select Device Screen for Repair Bad Sectors Tool	68
Figure 39 - Check Bad Sectors pop-up window	70
Figure 40 - Check and Recover Bad Sectors pop-up window 1	71
Figure 41 - Check and Recover Bad Sectors pop-up window 2	72
Figure 42 - Recover Bad Sectors Tool Screen	73



Objective

This document describes what is necessary to run the Lenovo UEFI Diagnostic tests.

Install and Run the UEFI diagnostics

Note: No installation is required for the embedded UEFI Diagnostics.

Download the Bootable UEFI Diagnostics and Create a Bootable USB Flash Drive Using Windows GUI

1. Save the UEFI Diagnostics image:

- a. Go to www.Lenovo.com/diags
- b. Click "Downloads."
- c. Under "Lenovo UEFI Bootable Diagnostics," click on "UEFI Bootable USB Generator. Save the file. (If your system has an Atom CPU, then click on "Lenovo UEFI Diagnostics – Bootable USB for Atom CPU based Tablet – ThinkPad 10" instead.)

2. Save the Bootable Generator:

- a. Go to www.Lenovo.com/diags
- b. Click "Downloads."
- c. Under "Lenovo UEFI Bootable Diagnostics," click on "UEFI Bootable ISO Generator (GUI).
- 3. Run the Bootable Generator program.
 - a. Go to the folder where you saved the bootable generator and double click on it.
 - b. Double click "BootableGenerator.exe."
 - c. Insert a USB flash drive.
 - d. Your flash drive name will appear under "Select a device." Click to select it. If you want to, you can type a new name for the device.
 - e. Click "Search." Click on the image name that you saved in step 1.
 - f. Click "Generate."
 - g. A message will appear, warning that all existing files on the flash drive will be erased if you continue. If you are OK with that, then press "Yes" to continue.

Run the UEFI Diagnostics

2.2.1 Run the UEFI Diagnostics from a Bootable Flash Drive

1. Create the Bootable flash drive, as explained in section 2.1.



- 2. If Secure Boot is enabled in BIOS, disable it.
- 3. Insert the flash drive.
- 4. Restart the machine, then immediately, press F12.
- On the boot menu, select your usb flash drive, and press Enter.
 The UEFI diagnostics menu will display on your screen.

2.2.2 Run the Embedded UEFI Diagnostics

Boot the system, then immediately press:

- F10 for Think systems
- F11 for Idea systems

The UEFI diagnostics menu will display on your screen.



Main Screen

The main screen for UEFI Lenovo Diagnostics is shown in Figure 1.

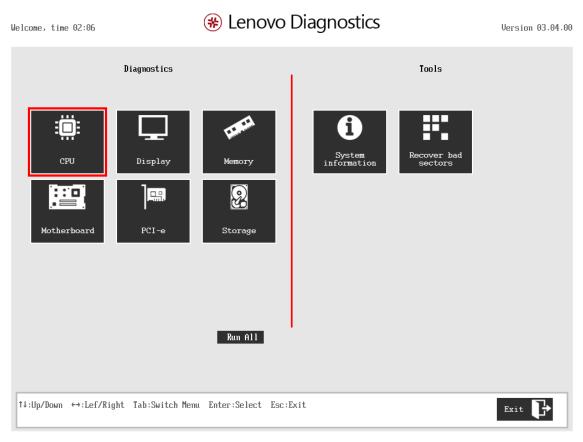


Figure 2 - Application Main Screen

The main screen is displayed right after the machine is booted from a USB flash drive containing the application. The Main Screen provides options to run all available device tests installed in the machine, options to see detailed information about the machine devices, and options to exit the application. The Main Screen is composed of:

- An Application Title Bar
- Two main sections (Diagnostics and Tools)
- An Instruction Bar

The Application Title Bar contains the name of the application and the Instruction Bar contains instructions for using the application. The Main Screen has two main sections: Diagnostics and Tools. The Diagnostics section provides options to run all installed tests and an option to exit the application. The Tools section provides options to use several tools.

Page | 9

The currently selected option is squared in red. The other options are not squared. The user can change the selected option by pressing the arrow keys. The up and down arrow keys are used to change the selected option in the same section (Diagnostics or Tools). The tab key is used to change the section (from Diagnostics to Tools, and vice versa). To run the selected option, the user must press the ENTER key.

Diagnostics options are:

- CPU
 - CPU Quick Test
 - CPU Extended Test
- Display
- Memory
- Motherboard
- PCI-e
- Storage

Tools options are:

- System Information
- Recover Bad Sectors tools

The "Memory quick test" is an option that runs memory quick test and displays the memory quick test screen.

The "Memory extended test" is an option that runs the memory extended test and displays the memory extended test screen.

The "Memory bit fade test (180 min)" is an option that runs the memory bit fade test and displays the memory bit fade test screen.

The "Quick storage device test" is an option that runs the storage device quick test and displays the storage device quick test Screen.

The "LCD test" is an option that runs the LCD test and displays the LCD test screen.

Page 10

The "PCI-e test" is an option that runs the PCI express test and displays the PCI express test screen.

The "RAID test" is an option that runs the RAID test and displays the RAID test screen.

The "Motherboard test" is an option that runs the Motherboard test and displays the Motherboard test screen.

The "Optical device test" is an option that runs the Optical device test and displays the Optical device test screen.

The "CPU quick test" is an option that runs the cpu quick test and displays the CPU quick test screen.

The "CPU extended test" is an option that runs the CPU extended test and displays the CPU extended test screen.

The "Exit Application" is an option that closes the application;

"System Information" option, displays tabs with the machine and memory information displaying "System Information" screen.

The "Generate configuration file" allows the user to generate a configuration file with several saved diagnostics.

The "Execute from configuration file" runs all diagnostics saved on the configuration file, and The "Recover Bad Sectors Tool" is an option that runs the bad sectors recovering operation and displays "Recover Bad Sectors Tools" screen.

		UEFI — User Guide
Page 11 WHO DO.		
CPU		
Welcome, time 02:57	🛞 Lenovo Diagnostics	Version 03.04.00
	Diagnostics Type:	
	[x]CPU Quick Test []CPU Extended Test	
	Next	
11:Up/Down Tab:Switch Menu Space Bar	:Check/Uncheck Enter:Select F1:Help for sele	ection ESC:Back to home

Figure 3 – CPU screen

CPU Quick Test

The system allows the user to access the CPU quick test diagnostic from the Main screen -> Diagnostics -> CPU.

The currently selected option has a "x" in front of the option. To access the CPU quick test diagnostic on screen, the user can press the UP/DOWN arrow keys until the "CPU quick test" and press SPACE Key to select it.

To run selected option user has to press the ENTER key on button "Next". After that, the system will show a list of tests, as illustrated in Figure 4 below, and all the tests are initially selected to be tested ('X' between brackets means the test is selected).

The user can deselect a selected test by pressing the SPACE key when test is highlighted. An empty space will appear between the brackets. To select a test again, the user can press the SPACE key again.



Initially, the "Select/deselect all option" is selected. If the user presses the SPACE key or ENTER key on that option, then all test options will be deselected. If the user selects the "Select/deselect all option" again, all tests options will also be selected again.

Welcome, time 1	8:57	🏶 Ler	novo Dia	gnostics		Version 03.04.00
		-	Select Algorit	hm :		
6		[[[[[[[[xlSelect / Dese xlRegister test xlBt Instructio xlX07 Floating xlMMX test xl3D Now! test xlSSE test xlAES test	n test		
			Run Tests 占			
†↓:Up/Down Ta	ab:Switch Menu	Space Bar:Check/Uncheck	Enter:Select	F1:Help for select	tion ESC:Back to home	Home

Figure 5 – CPU quick test

At least one test must be selected so the application can run the diagnostic. After the user chooses which tests must be performed, the user can select the "Run Tests" option by pressing the ENTER key. The system will run all tests, as illustrated in **Error! Reference source not found.** below. The user can a lso press the ESC key to go back to the Main Screen.

	Page 13	/HO DO.		
₩e	lcome, time 18:57	🛞 Lenov	o Diagnostics	Version 03.04.00
			tics Progress: PU	
		Information	Resu 1ª	ts
2	Test: # of test: Progress of cur Progress of dia		Final Result Code: CPU Started at: Register test Bt Instruction test X87 Floating Point test MMX test 3D Now! test SSE test AES test Result code: Finished at:	2016/17/07 18:58:23 PASSED IN PROGRESS WAITING WAITING WAITING WAITING WAITING
	†↓:Up/Down Tab:Switch	Menu Enter:Select Esc:Stop tests		Stop Tests

Figure 6 - CPU quick test progress

The CPU diagnostics progress screen provides information about the CPU progress, as well as information about the results. This screen is composed of:

- Application Title Bar;
- Screen Title Bar;

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- Two sections (Information and Results);
- Instruction Bar;

Application Title Bar contains the name of the application, Screen Title Bar contains the name of screen (in the case, CPU), Instruction Bar contains instructions to run the test. The CPU screen has also two main sections: Information and Results. The first section provides information about the test and diagnostic progress, and the second section provides information about the results of the test and the test algorithms.

The information section contains the following information:

• Test (name of test being currently run);



- # of Test (number of the current test among all tests to be run);
- Progress of current test (bar with progress in percentage of current test);
- Progress of diagnostic (bar with progress in percentage of all diagnostic, with its entire test).

The Results section contains the following information:

- Final Result Code: (an encrypted code that informs which modules were tested);
- Date and time that test has started;
- A list with all the algorithms which compose device test and their respective status (an algorithm can have six status:
 - ON QUEUE, indicating test is waiting to be run;
 - ON PROGRESS, indicating test is being run;
 - o PASSED, indicating algorithm has found no problems at device;
 - o FAILED, indicating that algorithm has found one or more faults at algorithm;
 - CANCELED, indicating algorithm was canceled by user;
 - o NOT SUPPORTED, indicating algorithm is not supported by device),
- Result Code for test:
- Date and time that the tests are finished (displayed after test is finished);
- Elapsed time, that is a duration of test in hours, minutes and seconds (displayed after test is finished).

While the diagnostic is running, the user can stop it at any time by pressing the ESC key. If the user does that, the diagnostic is aborted and the status of the test that is being run is changed to CANCELED. After the diagnostic is finished or canceled, the user can go back to the Main Screen (by pressing ESC key again) or see the test log (by pressing the F3 key).



CPU Extended Test

The system allows the user to access the CPU Extended Test diagnostic from the Main screen -> Diagnostics -> CPU.

The currently selected option has a "x" in front of the option. To access the CPU Extended Test diagnostic, the user can press the UP/DOWN arrow keys until the "CPU Extend Test" option inside CPU module. To run selected option user has to press the ENTER key on button "Next". When the user presses ENTER, the application will run the "Stress test", and it will take about 10 minutes to complete.

The CPU diagnostics progress screen provides information about the CPU progress, as well as information about the results. This screen is composed of:

- Application Title Bar;
- Screen Title Bar;
- Two sections (Information and Results);
- Instruction Bar;

Application Title Bar contains the name of the application, Screen Title Bar contains the name of screen (in the case, CPU), Instruction Bar contains instructions to run the test. The CPU screen has also two main sections: Information and Results. The first section provides information about the test and diagnostic progress, and the second section provides information about the results of the test and the test algorithms.

The information section contains the following information:

- Test (name of test being currently run);
- # of Test (number of the current test among all tests to be run);
- Progress of current test (bar with progress in percentage of current test);
- Progress of diagnostic (bar with progress in percentage of all diagnostic, with its entire test).

The Results section contains the following information:

- Final Result Code: (an encrypted code that informs which modules were tested);
- Date and time that test has started;



- A list with all the algorithms which compose device test and their respective status (an algorithm can have six status:
 - ON QUEUE, indicating test is waiting to be run;
 - ON PROGRESS, indicating test is being run;
 - PASSED, indicating algorithm has found no problems at device;
 - o FAILED, indicating that algorithm has found one or more faults at algorithm;
 - CANCELED, indicating algorithm was canceled by user;
 - NOT SUPPORTED, indicating algorithm is not supported by device),
- Result Code for test:
- Date and time that the tests are finished (displayed after test is finished);
- Elapsed time, that is a duration of test in hours, minutes and seconds (displayed after test is finished).

While the diagnostic is running, the user can stop it at any time by pressing the ESC key. If the user does that, the diagnostic is aborted and the status of the test that is being run is changed to CANCELED. After the diagnostic is finished or canceled, the user can go back to the Main Screen (by pressing ESC key again) or see the test log (by pressing the F3 key).

Display

After the user starts the "Display Test" option, the application computes the number of algorithms that can be performed by the test. If the test has more than one algorithm, "Select Algorithms" is displayed, as shown in **Error! Reference source not found.**.

Page 17		UEFI — User Guiae
Welcome, time 19:47	Lenovo Diagnostics	Version 03.04.00
	Select Algorithm:	
	[x]Select / Deselect All Options[x]Red solid color test[x]Blue solid color test[x]Green solid color test[x]Black solid color test[x]White solid color test[x]White solid color test[x]Uninance UESA test[x]Geometry UESA test[x]Focus UESA test[x]Combination test	
		[₃
	Run Tests	
†↓:Up/Down Tab:Switch Menu Space	Bar:Check/Uncheck Enter:Select F1:Help for select	ion ESC:Back to home Home

UEFI – User Guide

Figure 7 - Select Algorithms Screen

The "Select Algorithm" screen allows the user to select which algorithms will be tested by the application. After the user chooses at least one test and chooses the "Run Tests" option on the "Select Algorithms" screen, the Display tests starts:

Before an algorithm is run, a window containing instructions about the algorithm is displayed, as shown in Figure 6. The User can press the 'Enter' key to proceed with the algorithm execution or can press 'Esc' to abort the test.

e, time 19:56	🛞 Lenovo Diagnostics	Version 0
	Diagnostics Progress:	
your screen, cl	en will be red. Check to see if any pixels are not red in color ick, touch or press Enter key to continue. firm or ESC to cancel.	r. After checking 18
	Geometry UESA test Focus UESA test	WAITING WAITING

Figure 8 - Window is displayed with instructions for user about current LCD test

If the user chooses to proceed with running the test, an image pattern will be displayed on the screen, as shown in Error! Reference source not found.. After the user checks the LCD, any key can be pressed to



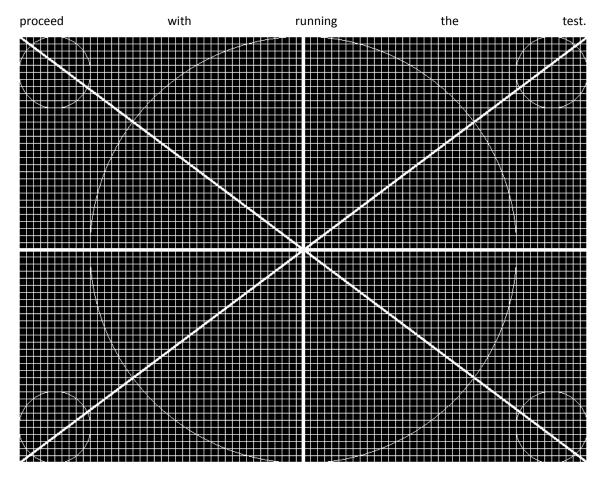


Figure 9 - Screen painted with pattern of current LCD test

After that, a window is displayed, asking the user if the pattern was painted correctly on the Display screen. If so, the user must press the 'Y' key; if not, the user must press the 'N' key. This window can be seen in **Error! Reference source not found.**



Welco	ome, time 20:00	🛞 Lenovo	Diagnostics	Version 03.04.00
			s Progress: play	
	In Test: Focu # of test: 8 of Progress of current to Progress of diagnostic	Was your screen painted corr Press YES to confirm or NO to YES	US VESA ectly? o cancel. NU Luminance VESA test Geometry VESA test Focus VESA test Combination test Result code: Finished at:	 2016/17/07 19:56:18 PASSED PASSED PASSED PASSED PASSED PASSED IN PROGRESS WAITING
ţţ	:Up/Down Tab:Switch Menu	Enter:Select Esc:Stop tests		Stop Tests

Figure 10 - Window asking user if screen was painted correctly

This process is repeated for each selected algorithm. After the test is finished or canceled, the user can go back to the Main Screen by pressing the ESC key again or to the Log Screen by pressing the F3 key.

Fan Test

After the user starts the "PCI-e" option, the application computes the number of algorithms that can be performed by the test and starts the test, as shown in **Error! Reference source not found.**.



	Fan tes	ST			
INFORMATION	RI	ESULTS			
	48C	tarted	at:	2014/12/23	10:40:12
Test: Control t # of test: 1 o	E a	an ontrol	test	IN	PROGRESS
Progress of current test 75% Progress of diagnostic	/ Re	esult (code:		
28%	١.				

Figure 11 - Fan test screen

The Fan diagnostic progress screen provides information about the Fan progress, as well as information about the results. This screen is composed of:

- Application Title Bar;
- Screen Title Bar;
- Two sections (Information and Results);
- Instruction Bar;

Application Title Bar contains the name of the application, Screen Title Bar contains the name of screen (in the case, Fan), Instruction Bar contains instructions to run the test. The Fan screen has also two main sections: Information and Results. The first section provides information about the test and diagnostic progress, and the second section provides information about the results of the test and the test algorithms.

The information section contains the following information:

• Test (name of test being currently run);



- # of Test (number of the current test among all tests to be run);
- Progress of current test (bar with progress in percentage of current test);
- Progress of diagnostic (bar with progress in percentage of all diagnostic, with its entire test).

The Results section contains the following information:

- Final Result Code: (an encrypted code that informs which modules were tested);
- Date and time that test has started;
- A list with all the algorithms which compose device test and their respective status (an algorithm can have six status:
 - ON QUEUE, indicating test is waiting to be run;
 - ON PROGRESS, indicating test is being run;
 - o PASSED, indicating algorithm has found no problems at device;
 - o FAILED, indicating that algorithm has found one or more faults at algorithm;
 - CANCELED, indicating algorithm was canceled by user;
 - o NOT SUPPORTED, indicating algorithm is not supported by device),
- Result Code for test:
- Date and time that the tests are finished (displayed after test is finished);
- Elapsed time, that is a duration of test in hours, minutes and seconds (displayed after test is finished).

While the diagnostic is running, the user can stop it at any time by pressing the ESC key. If the user does that, the diagnostic is aborted and the status of the test that is being run is changed to CANCELED. After the diagnostic is finished or canceled, the user can go back to the Main Screen (by pressing ESC key again) or see the test log (by pressing the F3 key).



Memory

Memory quick test

The Memory quick test Screen is shown in Error! Reference source not found..

Figure 12 - Memory – Quick test Screen

The system allows the user to access the Memory Quick Test diagnostic from the Main screen -> Diagnostics -> Memory.

The Memory diagnostics progress screen provides information about the Memory progress, as well as information about the results. This screen is composed of:

- Application Title Bar;
- Screen Title Bar;
- Two sections (Information and Results);
- Instruction Bar;



Application Title Bar contains the name of the application, Screen Title Bar contains the name of screen (in the case, Memory), Instruction Bar contains instructions to run the test. The Memory screen has also two main sections: Information and Results. The first section provides information about the test and diagnostic progress, and the second section provides information about the results of the test and the test algorithms.

The information section contains the following information:

- Test (name of test being currently run);
- # of Test (number of the current test among all tests to be run);
- Progress of current test (bar with progress in percentage of current test);
- Progress of diagnostic (bar with progress in percentage of all diagnostic, with its entire test).

The Results section contains the following information:

- Final Result Code: (an encrypted code that informs which modules were tested);
- Date and time that test has started;
- A list with all the algorithms which compose device test and their respective status (an algorithm can have six status:
 - ON QUEUE, indicating test is waiting to be run;
 - ON PROGRESS, indicating test is being run;
 - PASSED, indicating algorithm has found no problems at device;
 - o FAILED, indicating that algorithm has found one or more faults at algorithm;
 - CANCELED, indicating algorithm was canceled by user;
 - NOT SUPPORTED, indicating algorithm is not supported by device),
- Result Code for test:
- Date and time that the tests are finished (displayed after test is finished);
- Elapsed time, that is a duration of test in hours, minutes and seconds (displayed after test is finished).



While the diagnostic is running, the user can stop it at any time by pressing the ESC key. If the user does that, the diagnostic is aborted and the status of the test that is being run is changed to CANCELED. After the diagnostic is finished or canceled, the user can go back to the Main Screen (by pressing ESC key again) or see the test log (by pressing the F3 key).

Memory Extended Tests

The system allows the user to access the Memory Extended Diagnostic from the Main screen -> Diagnostics -> Memory.

The currently selected option has a "x" in front of the option. To access the Memory Extended Test diagnostic on screen, the user can press the UP/DOWN arrow keys until the "CPU quick test" and press SPACE Key to select it.

To run selected option user has to press the ENTER key on button "Next". After that, the system will show a list of tests, as illustrated in Figure 11 below, and all the tests are initially selected to be tested ('X' between brackets means the test is selected).

The user can deselect a selected test by pressing the SPACE key when test is highlighted. An empty space will appear between the brackets. To select a test again, the user can press the SPACE key again.

Initially, the "Select/deselect all option" is selected. If the user presses the SPACE key or ENTER key on that option, then all test options will be deselected. If the user selects the "Select/deselect all option" again, all tests options will also be selected again.

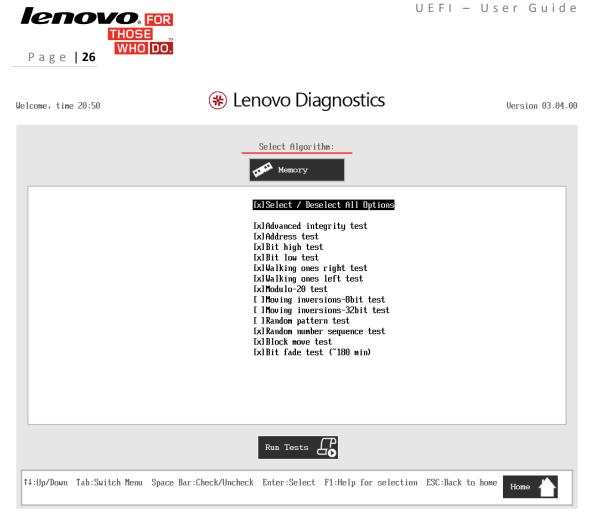


Figure 13 - Memory extended test

At least one test must be selected so the application can run the diagnostic. After the user chooses which tests must be performed, the user can select the "Run Tests" option by pressing the ENTER key. The system will run all tests, as illustrated in **Error! Reference source not found.** below. The user can a lso press the ESC key to go back to the Main Screen.

Welcom	e, time 20:50	🛞 Lenov	o Diagnostics	Version 03.0
			stics Progress: Memory	
		Information	Results	
	Test: # of test: Progress of cu Progress of di		Final Result Code: MEMORY Started at: Advanced integrity test Address test Bit high test Bit low test Walking ones right test Walking ones left test Modulo-20 test Moving inversions-32bit test Random pattern test Random number sequence test	2016/17/07 20:50:51 IN PROGRESS WAITING WAITING WAITING WAITING WAITING WAITING WAITING WAITING WAITING WAITING WAITING
†∔:L	Jp/Down Tab:Switc	h Menu Enter:Select Esc:Stop tests	;	Stop Tests

Figure 14 - Memory extended test progress

The Memory diagnostics progress screen provides information about the Memory progress, as well as information about the results. This screen is composed of:

- Application Title Bar;
- Screen Title Bar;

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- Two sections (Information and Results);
- Instruction Bar;

Application Title Bar contains the name of the application, Screen Title Bar contains the name of screen (in the case, Memory), Instruction Bar contains instructions to run the test. The Memory screen has also two main sections: Information and Results. The first section provides information about the test and diagnostic progress, and the second section provides information about the results of the test and the test algorithms.

The information section contains the following information:

• Test (name of test being currently run);



- # of Test (number of the current test among all tests to be run);
- Progress of current test (bar with progress in percentage of current test);
- Progress of diagnostic (bar with progress in percentage of all diagnostic, with its entire test).

The Results section contains the following information:

- Final Result Code: (an encrypted code that informs which modules were tested);
- Date and time that test has started;
- A list with all the algorithms which compose device test and their respective status (an algorithm can have six status:
 - ON QUEUE, indicating test is waiting to be run;
 - ON PROGRESS, indicating test is being run;
 - o PASSED, indicating algorithm has found no problems at device;
 - o FAILED, indicating that algorithm has found one or more faults at algorithm;
 - CANCELED, indicating algorithm was canceled by user;
 - o NOT SUPPORTED, indicating algorithm is not supported by device),
- Result Code for test:
- Date and time that the tests are finished (displayed after test is finished);
- Elapsed time, that is a duration of test in hours, minutes and seconds (displayed after test is finished).

While the diagnostic is running, the user can stop it at any time by pressing the ESC key. If the user does that, the diagnostic is aborted and the status of the test that is being run is changed to CANCELED. After the diagnostic is finished or canceled, the user can go back to the Main Screen (by pressing ESC key again) or see the test log (by pressing the F3 key).



Motherboard Test

After the user starts "Motherboard test" option, the application computes the number of algorithms that can be performed by the test. If the test has more than one algorithm, "Select Algorithms" is displayed, as shown in **Error! Reference source not found.**.

Figure 15 - Select Algorithm Screen

The system allows the user to access the Motherboard Diagnostic from the Main screen -> Diagnostics -> Motherboard.

The currently selected option has a "x" in front of the option. To run selected option user has to press the ENTER key on button "Next". After that, the system will show a list of tests, as illustrated in Figure 13 above, and all the tests are initially selected to be tested ('X' between brackets means the test is selected).



The user can deselect a selected test by pressing the SPACE key when test is highlighted. An empty space will appear between the brackets. To select a test again, the user can press the SPACE key again.

Initially, the "Select/deselect all option" is selected. If the user presses the SPACE key or ENTER key on that option, then all test options will be deselected. If the user selects the "Select/deselect all option" again, all tests options will also be selected again.

At least one test must be selected so the application can run the diagnostic. After the user chooses which tests must be performed, the user can select the "Run Tests" option by pressing the ENTER key. The system will run all tests, as illustrated in **Error! Reference source not found.** below. The user can a lso press the ESC key to go back to the Main Screen.

Welcome, time 21:07	Lenovo Diagnostics Diagnostics Progress: Image: Motherboard	Version 03.04.00
Information Test: RTC test # of test: 3 of 6 Progress of current test - 50 % Progress of diagnostics - 41 %	Final Result Code: MOTHERBOARD Started at: Chipset test PCI/PCIe test RTC test USB test DMA test IRQ test Result code: Finished at:	Results 2016/17/07 21:07:48 PASSED PASSED IN PROGRESS WAITING WAITING WAITING WAITING
↑↓:Up/Down Tab:Switch Menu Enter:Select E	Ssc:Stop tests	Stop Tests

Figure 16 - Motherboard test screen

UEFI – User Guide

Page | 31

The Motherboard diagnostics progress screen provides information about the Motherboard progress, as well as information about the results. This screen is composed of:

- Application Title Bar;
- Screen Title Bar;
- Two sections (Information and Results);
- Instruction Bar;

Application Title Bar contains the name of the application, Screen Title Bar contains the name of screen (in the case, Memory), Instruction Bar contains instructions to run the test. The Memory screen has also two main sections: Information and Results. The first section provides information about the test and diagnostic progress, and the second section provides information about the results of the test and the test algorithms.

The information section contains the following information:

- Test (name of test being currently run);
- # of Test (number of the current test among all tests to be run);
- Progress of current test (bar with progress in percentage of current test);
- Progress of diagnostic (bar with progress in percentage of all diagnostic, with its entire test).

The Results section contains the following information:

- Final Result Code: (an encrypted code that informs which modules were tested);
- Date and time that test has started;
- A list with all the algorithms which compose device test and their respective status (an algorithm can have six status:
 - ON QUEUE, indicating test is waiting to be run;
 - ON PROGRESS, indicating test is being run;
 - PASSED, indicating algorithm has found no problems at device;
 - o FAILED, indicating that algorithm has found one or more faults at algorithm;
 - CANCELED, indicating algorithm was canceled by user;
 - NOT SUPPORTED, indicating algorithm is not supported by device),



- Result Code for test:
- Date and time that the tests are finished (displayed after test is finished);
- Elapsed time, that is a duration of test in hours, minutes and seconds (displayed after test is finished).

While the diagnostic is running, the user can stop it at any time by pressing the ESC key. If the user does that, the diagnostic is aborted and the status of the test that is being run is changed to CANCELED. After the diagnostic is finished or canceled, the user can go back to the Main Screen (by pressing ESC key again) or see the test log (by pressing the F3 key).

PCI-e Test

After the user starts the "PCI-e" option, the application computes the number of algorithms that can be performed by the test and starts the test, as shown in **Error! Reference source not found.**.



The PCI-e diagnostic progress screen provides information about the PCI progress, as well as information about the results. This screen is composed of:

- Application Title Bar;
- Screen Title Bar;
- Two sections (Information and Results);
- Instruction Bar;

Application Title Bar contains the name of the application, Screen Title Bar contains the name of screen (in the case, Memory), Instruction Bar contains instructions to run the test. The Memory screen has also two main sections: Information and Results. The first section provides information about the test and diagnostic progress, and the second section provides information about the results of the test and the test algorithms.

The information section contains the following information:

- Test (name of test being currently run);
- # of Test (number of the current test among all tests to be run);
- Progress of current test (bar with progress in percentage of current test);
- Progress of diagnostic (bar with progress in percentage of all diagnostic, with its entire test).

The Results section contains the following information:

- Final Result Code: (an encrypted code that informs which modules were tested);
- Date and time that test has started;
- A list with all the algorithms which compose device test and their respective status (an algorithm can have six status:
 - ON QUEUE, indicating test is waiting to be run;
 - ON PROGRESS, indicating test is being run;
 - PASSED, indicating algorithm has found no problems at device;
 - FAILED, indicating that algorithm has found one or more faults at algorithm;
 - o CANCELED, indicating algorithm was canceled by user;



- o NOT SUPPORTED, indicating algorithm is not supported by device),
- Result Code for test:
- Date and time that the tests are finished (displayed after test is finished);
- Elapsed time, that is a duration of test in hours, minutes and seconds (displayed after test is finished).

While the diagnostic is running, the user can stop it at any time by pressing the ESC key. If the user does that, the diagnostic is aborted and the status of the test that is being run is changed to CANCELED. After the diagnostic is finished or canceled, the user can go back to the Main Screen (by pressing ESC key again) or see the test log (by pressing the F3 key).

RAID Test

After the user selects "Raid" option, the application will display the number of Raid devices installed in the machine. If there is more than one raid device installed in the machine, the menu "Select Device" is displayed, as shown in **Error! Reference source not found.**.



<pre>RAID test SELECT TESTS [x] Select/Deselect All [x] Bus: 0X4 Dev: 0X0 Vendor: 0X1000 [x] Bus: 0X5 Dev: 0X1 Vendor: 0X1001 Run test > Mun test > </pre>	Lenovo dia	agnostics	12:00:00
<pre>[x] Select/Deselect All [x] Bus: 0X4 Dev: 0X0 Vendor: 0X1000 [x] Bus: 0X5 Dev: 0X1 Vendor: 0X1001 Run test ></pre>		RAID test	
<pre>[x] Select/Deselect All [x] Bus: 0X4 Dev: 0X0 Vendor: 0X1000 [x] Bus: 0X5 Dev: 0X1 Vendor: 0X1001 Run test ></pre>			
		<pre>[x] Select/Deselect All [x] Bus: 0X4 Dev: 0X0 Vendor: 0X1000 [x] Bus: 0X5 Dev: 0X1 Vendor: 0X1001</pre>	
		L	
		rrows:navigation Space bar:check/uncheck ESC-r	exit
	A	Version XX.XX.XX	SALC

Figure 18 - RAID test selecting device

The currently selected option has a "x" in front of the option. To run selected option user has to press the ENTER key on button "Next". After that, the system will show a list of tests, as illustrated in Figure 16 above, and all the tests are initially selected to be tested ('X' between brackets means the test is selected).

The user can deselect a selected test by pressing the SPACE key when test is highlighted. An empty space will appear between the brackets. To select a test again, the user can press the SPACE key again.

Initially, the "Select/deselect all option" is selected. If the user presses the SPACE key or ENTER key on that option, then all test options will be deselected. If the user selects the "Select/deselect all option" again, all tests options will also be selected again.

At least one device must be selected so the application can run the diagnostic. After the user chooses which devices must be performed, the user can select the "Next" option by pressing the ENTER



key. The system will show the screen where user can select the tests wants to performed for selected devices.

Lenovo diagnostics	12:00:00
RAID test	
SELECT TESTS	
[x] Select/Deselect All	
[X] Select/Deselect All	
[x] Status test	
[x] Slot test	
[x] Link test [x] Advanced error test	
[x] Advanced error test	
Run test >	
Arrows:navigation Space bar:check/uncheck	ESC:exit
Version XX.XX.XX	

Figure 19 - RAID selecting tests

Initially, the "Select/deselect all" option is selected. If the user deselects this option by pressing SPACE, then all the test options will be deselected. If the user selects the "Select/deselect all" option again, all the test options will be selected again.

At least one test must be selected so that the application can run the diagnostic. After the user chooses which tests will be performed, the user can press the ENTER key or select the RUN TEST option and press the SPACE key. The system will run the tests, as illustrated in **Error! Reference source not found.** b elow. The User can also press the ESC key to go back to the Main Screen.

The screen will list the tests that can be performed for each selected device type. At least one test must be selected so the application can run the diagnostic. After the user chooses which devices must be performed, the user can select the "Run Test" option by pressing the ENTER. It will start the diagnostic.



INFORMATION	TEST RESULTS	
Bus:XXXX Dev:XXXX Vendor:XXXXXX Test: Status test	Started at: 2013/01/01 16:26:25	;
# of test: 1 of 4	> Bus:XXXX Dev:XXXX Vendor:XXXXXX	
	Status test IN PROGRESS	3
	Slot test WAITING	3
Progress of current test	Link test WAITING	
75%	Advanced error test WAITING	ž
Progress of diagnostic	Result code:	_
28%	Finnished at:	-
	Total time:	-
	> Bus:XXXX Dev:XXXX Vendor:XXXXXX	
	Status test IN PROGRESS	5
	Slot test WAITING	÷
	Link test WAITING	- B
	Advanced error test WAITING	÷
	Result code:	

Figure 20 - RAID test progress

The Storage diagnostic progress screen provides information about the Storage progress, as well as information about the results. This screen is composed of:

- Application Title Bar;
- Screen Title Bar;
- Two sections (Information and Results);
- Instruction Bar;

Application Title Bar contains the name of the application, Screen Title Bar contains the name of screen (in the case, Memory), Instruction Bar contains instructions to run the test. The Memory screen has also two main sections: Information and Results. The first section provides information about the test and diagnostic progress, and the second section provides information about the results of the test and the test algorithms.

The information section contains the following information:

• Test (name of test being currently run);



- # of Test (number of the current test among all tests to be run);
- Progress of current test (bar with progress in percentage of current test);
- Progress of diagnostic (bar with progress in percentage of all diagnostic, with its entire test).

The Results section contains the following information:

- Final Result Code: (an encrypted code that informs which modules were tested);
- Date and time that test has started;
- A list with all the algorithms which compose device test and their respective status (an algorithm can have six status:
 - ON QUEUE, indicating test is waiting to be run;
 - ON PROGRESS, indicating test is being run;
 - o PASSED, indicating algorithm has found no problems at device;
 - o FAILED, indicating that algorithm has found one or more faults at algorithm;
 - CANCELED, indicating algorithm was canceled by user;
 - o NOT SUPPORTED, indicating algorithm is not supported by device),
- Result Code for test:
- Date and time that the tests are finished (displayed after test is finished);
- Elapsed time, that is a duration of test in hours, minutes and seconds (displayed after test is finished).

While the diagnostic is running, the user can stop it at any time by pressing the ESC key. If the user does that, the diagnostic is aborted and the status of the test that is being run is changed to CANCELED. After the diagnostic is finished or canceled, the user can go back to the Main Screen (by pressing ESC key again) or see the test log (by pressing the F3 key).



Storage Test

After the user selects "Storage" option, the application will display the number of storage devices installed in the machine. If there is more than one storage device installed in the machine, the menu "Select Device" is displayed, as shown in **Error! Reference source not found.**.

This screen has also an option where user can view the devices details. To access this feature user has to highlight the device that wants to see details and press F1 key, it will open a popup on screen with device details, as shown in **Error! Reference source not found.**

Welcome, time	21:16	🛞 Ler	novo Dia	gnostic	S		Version	03.04.00
		ī	Select Device	2:				
		-	xlSelect / Dese xlHTS725050A7E(xlSSD-SanDisk		ions O O			
			Next 🜔					
†∔:Up/Down	Tab:Switch Menu	Space Bar:Check/Uncheck	Enter:Select	F1:Help for	selection	ESC:Back to home	Home	

Figure 21 - Select Devices Screen



Welcome, time	21:17	🛞 Ler	novo Dia	gnostics		Version 03.04.00
		-	Select Devic	e:		
			x]Select / Des x]HTS725050A7E	elect All Options 635-H6ST	5 	
		Name: Manufacturer Device Type: Size:				
			Next			
†↓:Up/Down	Tab:Switch Menu	Space Bar:Check/Uncheck	Enter:Select	F1:Help for sele	ection ESC:Back to P	Home

Figure 22 - Select Devices Screen popup details

The currently selected option has a "x" in front of the option. To run selected option user has to press the ENTER key on button "Next". After that, the system will show a list of tests, as illustrated in Figure 19 above, and all the tests are initially selected to be tested ('X' between brackets means the test is selected).

The user can deselect a selected test by pressing the SPACE key when test is highlighted. An empty space will appear between the brackets. To select a test again, the user can press the SPACE key again.

Initially, the "Select/deselect all option" is selected. If the user presses the SPACE key or ENTER key on that option, then all test options will be deselected. If the user selects the "Select/deselect all option" again, all tests options will also be selected again.

At least one device must be selected so the application can run the diagnostic. After the user chooses which devices must be performed, the user can select the "Next" option by pressing the ENTER



key. The system will show the screen where user can select the tests wants to performed for selected devices.

Welcome, time 21:17	Henovo Diagnostics	Version 03.04.00
	Select Algorithm:	
	[x]Select / Deselect All Options SATA Device tests: [x]Smart status test [x]Smart short self-test [x]Drive self-test [x]Random seek test [x]Random seek test [x]Targeted read test SSD Device tests: [x]Smart status test [x]Smart status test [x]Smart status test [x]Smart short self-test [x]Targeted read test	0 0 0 0 0 0
	Run Tests	
†↓:Up/Down Tab:Sw	tch Menu Space Bar:Check/Uncheck Enter:Select F1:Help for selec	ction ESC:Back to home Home

Figure 23 - Select Tests Screen

The screen will list the tests that can be performed for each selected device type. The On example displayed on Figure 21, it's possible to see that user selected a "SATA" and "SSD" device types, so the tests that can be performed for each device as listed below them.

At least one test must be selected so the application can run the diagnostic. After the user chooses which devices must be performed, the user can select the "Run Test" option by pressing the ENTER. It will start the diagnostic.

Welcome, time 21:17	Lenovo Diagnostics	Version 03.04.00
	Diagnostics Progress:	
Information		Results
Test: Smart short s # of test: 2 of 9 Progress of current test - (Progress of diagnostics - 2	Started at: Smart status tes Smart short self	t PASSED -test IN PROGRESS WAITING WAITING WAITING
1↓:Up/Down Tab:Switch Menu Enter:Sel	ect Esc:Stop tests	Stop Tests

Figure 24 – Storage Test Screen

The Storage diagnostic progress screen provides information about the Storage progress, as well as information about the results. This screen is composed of:

- Application Title Bar;
- Screen Title Bar;

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- Two sections (Information and Results);
- Instruction Bar;

Application Title Bar contains the name of the application, Screen Title Bar contains the name of screen (in the case, Memory), Instruction Bar contains instructions to run the test. The Memory screen has also two main sections: Information and Results. The first section provides information about the test and diagnostic progress, and the second section provides information about the results of the test and the test algorithms.

The information section contains the following information:

• Test (name of test being currently run);



- # of Test (number of the current test among all tests to be run);
- Progress of current test (bar with progress in percentage of current test);
- Progress of diagnostic (bar with progress in percentage of all diagnostic, with its entire test).

The Results section contains the following information:

- Final Result Code: (an encrypted code that informs which modules were tested);
- Date and time that test has started;
- A list with all the algorithms which compose device test and their respective status (an algorithm can have six status:
 - ON QUEUE, indicating test is waiting to be run;
 - ON PROGRESS, indicating test is being run;
 - o PASSED, indicating algorithm has found no problems at device;
 - o FAILED, indicating that algorithm has found one or more faults at algorithm;
 - CANCELED, indicating algorithm was canceled by user;
 - o NOT SUPPORTED, indicating algorithm is not supported by device),
- Result Code for test:
- Date and time that the tests are finished (displayed after test is finished);
- Elapsed time, that is a duration of test in hours, minutes and seconds (displayed after test is finished).

While the diagnostic is running, the user can stop it at any time by pressing the ESC key. If the user does that, the diagnostic is aborted and the status of the test that is being run is changed to CANCELED. After the diagnostic is finished or canceled, the user can go back to the Main Screen (by pressing ESC key again) or see the test log (by pressing the F3 key).



Optical Device Test

The system allows the user to access the Memory Extended Diagnostic from the Main screen -> Diagnostics -> Memory.

The currently selected option has a "x" in front of the option. To access the Memory Extended Test diagnostic on screen, the user can press the UP/DOWN arrow keys until the "CPU quick test" and press SPACE Key to select it.

To run selected option user has to press the ENTER key on button "Next". After that, the system will show a list of tests, as illustrated in Figure 23 below, and all the tests are initially selected to be tested ('X' between brackets means the test is selected).

The user can deselect a selected test by pressing the SPACE key when test is highlighted. An empty space will appear between the brackets. To select a test again, the user can press the SPACE key again.

Initially, the "Select/deselect all option" is selected. If the user presses the SPACE key or ENTER key on that option, then all test options will be deselected. If the user selects the "Select/deselect all option" again, all tests options will also be selected again.



SELECT TESTS
[x] Select/Deselect All
[X] Select/Deselect All
[x] Media-less optical serf-test
[x] Linear seek test
[x] Random seek test
[x] Funnel seek test
[x] Read and compare test
[x] Write test
Run test >

Figure 25 - Select Algorithm Screen

At least one test must be selected so the application can run the diagnostic. After the user chooses which tests must be performed, the user can select the "Run Tests" option by pressing the ENTER key. The system will run all tests, as illustrated in **Error! Reference source not found.** above. The user can a lso press the ESC key to go back to the Main Screen.



INFORMATION	TEST RESULTS
Device: DVDRAM GT50N Test: Linear seek test # of test: 2 of 2	Started at: 2013/01/01 16:26:2 > DVDRAM GT50N Unnatended optical test PASSED
Progress of current test	Linear seek test PASSED
100% Progress of diagnostic 100%	Result code: UME01C000-518V5 Finished at: 2013/01/01 08:38:2 Total time: 00:00:0

Figure 26 - Optical Device Test screen

The Optical diagnostic progress screen provides information about the optical progress, as well as information about the results. This screen is composed of:

- Application Title Bar;
- Screen Title Bar;
- Two sections (Information and Results);
- Instruction Bar;

Application Title Bar contains the name of the application, Screen Title Bar contains the name of screen (in the case, Optical), Instruction Bar contains instructions to run the test. The Optical screen has also two main sections: Information and Results. The first section provides information about the test and diagnostic progress, and the second section provides information about the results of the test and the test algorithms.

The information section contains the following information:

• Test (name of test being currently run);



- # of Test (number of the current test among all tests to be run);
- Progress of current test (bar with progress in percentage of current test);
- Progress of diagnostic (bar with progress in percentage of all diagnostic, with its entire test).

The Results section contains the following information:

- Final Result Code: (an encrypted code that informs which modules were tested);
- Date and time that test has started;
- A list with all the algorithms which compose device test and their respective status (an algorithm can have six status:
 - ON QUEUE, indicating test is waiting to be run;
 - ON PROGRESS, indicating test is being run;
 - o PASSED, indicating algorithm has found no problems at device;
 - o FAILED, indicating that algorithm has found one or more faults at algorithm;
 - CANCELED, indicating algorithm was canceled by user;
 - o NOT SUPPORTED, indicating algorithm is not supported by device),
- Result Code for test:
- Date and time that the tests are finished (displayed after test is finished);
- Elapsed time, that is a duration of test in hours, minutes and seconds (displayed after test is finished).

While the diagnostic is running, the user can stop it at any time by pressing the ESC key. If the user does that, the diagnostic is aborted and the status of the test that is being run is changed to CANCELED. After the diagnostic is finished or canceled, the user can go back to the Main Screen (by pressing ESC key again) or see the test log (by pressing the F3 key).



Video Card test

The Video Card test is not able to end user, but it's possible to access it from ShellView. User has to type the command on shellview and the test is started. This test on shellview does not have the same used for end user, so it's not possible to stop test while it's being performed. User will know the result of the test on log generated by application after test diagnostic is finished.

Run All Tests

The system allows the user to access the Run all test diagnostic from the Main screen.

The currently selected option has a "x" in front of the option. To select the type of test that user wants to run, can be used the UP/DOWN arrow keys to navigated until the desired item. User can press SPACE Key to select it, as illustrated in Figure 25 below

The system will show a list of tests, and all the tests are initially selected to be tested ('X' between brackets means the test is selected).

The user can deselect a selected test by pressing the SPACE key when test is highlighted. An empty space will appear between the brackets. To select a test again, the user can press the SPACE key again.

Initially, the "Select/deselect all option" is selected. If the user presses the SPACE key or ENTER key on that option, then all test options will be deselected. If the user selects the "Select/deselect all option" again, all tests options will also be selected again.

To run selected option user has to press the ENTER key on button "Run Tests".

Page 49	0	Eri – Öser Gulue
Welcome, time 23:40	Lenovo Diagnostics	Version 03.04.00
	Select Algorithm:	
	[x]Quick tests [x]Extended tests	
	[x]Restricted tests to unattended only	
	l≩	
	Run Tests	
1↓:Up/Down Tab:Switch Menu Space Bar	:Check/Uncheck Enter:Select F1:Help for selection	ESC:Back to home Home

UEFI – User Guide

Figure 27 – Run All test

At least one test must be selected so the application can run the diagnostic. After the user chooses which tests must be performed, the user can select the "Run Tests" option by pressing the ENTER key. The system will run all tests, as illustrated in **Error! Reference source not found.** below. The user can a lso press the ESC key to go back to the Main Screen.

Run All is a test that runs all diagnostics included in the tool, such as CPU, LDC, Memory, Motherboard, Optical, PCI and Storage. The only choice the user has is: Quick, Extended or Restricted.

Welcome,	time 23:42 🛞 Leno	ovo D	iagnostics	Version 03.04.00
	Diagr		all	
	Information		Resu la	s
	Test: Stress test # of test: 8 of 37 Progress of current test - 18 % Progress of diagnostics - 18 %	*	Final Result Code: CPU Started at: Register test Bt Instruction test X87 Floating Point test MMX test 3D Now! test SSE test AES test Result code: Finished at: CPU	2016/17/07 23:40:51 PASSED PASSED PASSED NOT APPLICABLE PASSED UCP03F000-UL7BMK 2016/17/07 23:41:06
↑↓:Up,	'Down Tab:Switch Menu Enter:Select Esc:Stop tes	ts		Stop Tests

Figure 28 – Run all test progress

The Run all diagnostic progress screen provides information about the run all progress, as well as information about the results. This screen is composed of:

- Application Title Bar;
- Screen Title Bar;

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Page | 50

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- Two sections (Information and Results);
- Instruction Bar;

Application Title Bar contains the name of the application, Screen Title Bar contains the name of screen (in the case, Optical), Instruction Bar contains instructions to run the test. The Optical screen has also two main sections: Information and Results. The first section provides information about the test and diagnostic progress, and the second section provides information about the results of the test and the test algorithms.

The information section contains the following information:

• Test (name of test being currently run);



- # of Test (number of the current test among all tests to be run);
- Progress of current test (bar with progress in percentage of current test);
- Progress of diagnostic (bar with progress in percentage of all diagnostic, with its entire test).

The Results section contains the following information:

- Final Result Code: (an encrypted code that informs which modules were tested);
- Date and time that test has started;
- A list with all the algorithms which compose device test and their respective status (an algorithm can have six status:
 - ON QUEUE, indicating test is waiting to be run;
 - ON PROGRESS, indicating test is being run;
 - o PASSED, indicating algorithm has found no problems at device;
 - o FAILED, indicating that algorithm has found one or more faults at algorithm;
 - CANCELED, indicating algorithm was canceled by user;
 - o NOT SUPPORTED, indicating algorithm is not supported by device),
- Result Code for test:
- Date and time that the tests are finished (displayed after test is finished);
- Elapsed time, that is a duration of test in hours, minutes and seconds (displayed after test is finished).

While the diagnostic is running, the user can stop it at any time by pressing the ESC key. If the user does that, the diagnostic is aborted and the status of the test that is being run is changed to CANCELED. After the diagnostic is finished or canceled, the user can go back to the Main Screen (by pressing ESC key again) or see the test log (by pressing the F3 key).



Log Screen

After a test or a recover operation is finished or canceled, the user can see the "Log Screen" by pressing the 'L' key. The "Log Screen" for Memory Test is shown in **Error! Reference source not found.**.

Welcome, time 23:49	Lenovo Diagnostics	Version 03.04.00
	Log:	
Lenovo diagnostics Log Serial number: BIOS version: Machine model: Final Result Code: CPU QUICK DIAGNOSTIC 2016/07/17 23:40:5	PF03HQHD JBET56VW (1.21) ThinkPad T4508 XAFKSU1C-H96681 1	
Result code: Model: Vendor: Number of cores: Number of threads: Signature: Max speed: Current speed: Features: Cache L1: Cache L2: Cache L3:	UCP03F000-UL7BMK Intel(R) Core(TM) i5-5###U CPU @ 2.00GHz INTEL 2	R2, CLMUL,
Start tests:	Save log	
↑↓:Up/Down Tab:Switch Menu Enter:Select	F2:Save log Esc:Back to home	Home

Figure 29 - Log Screen for Quick Memory Test

"Log Screen" is composed of:

- Application Title Bar;
- Screen Title Bar;
- Instruction Bar;
- Log Content Region;
- Scroll Bar.

The Application Title Bar contains the name of the application;

Page | 53

Screen Title Bar contains name of screen (in the case, Log Screen);

Instruction Bar contains instructions to use screen and current time;

Log Content Region shows log content;

Scroll Bar shows which portion of all log is displayed at Log Content Region.

If the log content has more rows than screen, the user can scroll by pressing the Up and Down arrow keys to move the displayed region up and down, respectively. The user can also go back to the Main Screen by pressing the 'ESC' key and save the log by pressing the "F2" key.

Save Log Window

If the user chooses to save the log by pressing the "F2" key on the "Log Screen", the "Save Log" window is displayed, as shown in **Error! Reference source not found.**.

Figure 30- Save Log Window



The "Save Log" window is composed of:

- Window Title Bar;
- Saving Options List;
- Cancel Option.

The Window Title Bar contains the name of the window (in this case, Save Log);

The Save Log List shows all devices where the log can be saved;

Cancel Option is used to perform a cancel operation.

The currently selected option is highlighted in black. The user can change the selected option by pressing the up and down arrow keys. The user can choose which device to save the log in. After the user chooses a device, the user can press ENTER. The application will attempt to save the log on the selected device.

If the saving operation is successful, a window will be displayed to inform the user that the operation was successful (as shown in **Error! Reference source not found.**). If the operation does not w ork, a window will be displayed to inform the user that the operation was not successful. In both cases, the user must press ENTER, and the "Log Test" screen will be displayed again.



Welcome, time 00:02	🛞 Lenovo Diagnostics	Version 03.04.00
	Log:	
Lenovo diagnostics Log Serial number: BIOS version: Machine model: Final Result Code: CPU QUICK DIAGNOSTIC 2016/07. Result code: Model: Vendor: Number of cores: Number of threads: Signature: Max speed: Current speed: Features: Cache L1: Cache L2: Cache L3:	Message: Log saved at device UEFI 3-0. Press OK to continue. OK 2.7 GHz MMX, EM64T, SSE, SSE2, SSE3, SSSE3, SSE4.1, SSE4.2, FMA, PSE, PSE-36, IDA/Turbo boost, HTT, XD, VMX 2 x 32 KB Data, 2 x 32 KB Instruction 2 x 256 KB Unified 1 x 3 MB Unified	, AES, AVX, AVX2, CLMUL,
Start tests:		
t∔:Up/Down Tab:Switch Menu E	save log 📄	Home 🔶
L		

Figure 31 - Log saving operation was successful

If the user chooses not to save the log, he can select the Cancel option and press ENTER. Then, the Save Log window will be closed without saving the log.



System Information

The System Information Screen with System tab selected is shown in **Error! Reference source n** ot found.

Welcome, time 00:19	* I	enovo Diagnostics	Version 03.04.00
		System information:	
System System CFU Memory Display Storage CI-e	MACHINE INFORMATION Machine manufacturer Product name Product version Serial number BIOS INFORMATION BIOS Version BIOS version BIOS release date BIOS manufacturer PROCESSOR INFORMATION Processor manufacturer Processor version	LENOUO 2014080001 ThinkPad T450S PF03HQHD JBET56WW (1.21) 01/27/2016 LENOUO Intel(R) Corporation Intel(R) Corporation Intel(R) Core(TM) i5-5###U CPU @ 2.006Hz	
†↓:Up/Down Tab:Swit	ch Menu Enter:Select Esc:E	lack to home	Home

Figure 32 - System Information Screen – System Tab



System Information Screen with CPU tab selected is shown in Error! Reference source not f

ound.

Welcome, time 00:19		Henovo Diagnostics	Version	03.04.00
System	Model: Vendor: Number of cores: Number of threads: Signature: Max speed: Current speed: Features:	System information: Intel(R) Core(TM) i5-5###U CPU @ 2.00GHz INTEL 2 306d4 2.300 GHz 2.7 GHz MMX, EM64T, SSE, SSE2, SSE3, SSE4.1, SSE4.2, (θES.	
Display Motherboard Storage	Cache L1: Cache L2: Cache L3:	AVX, AVX2, CLMUL, FMA, PSE, PSE-36, IDA/Turbo boost, XD, UMX 2 × 32 KB Data, 2 × 32 KB Instruction 2 × 256 KB Unified 1 × 3 MB Unified		
†↓:Up/Down Tab:Swite	ch Menu Enter:Select	Esc:Back to home	Home	

Figure 33 - System Information Screen – CPU Tab



System Information Screen with Display tab selected is showed at Error! Reference source not f

ound.



Figure 34 - System Information Screen – Display Tab



The System Information Screen with Memory tab selected is shown in Error! Reference source n

ot found.

Welcome, time 00:19	(⊯ Le	enovo Diagnostics	Version 03.04.00
	-	System information:	
System System Memory Display Motherboard Storage PCI-e	Total physical memory: Drigin: Type: Manufacturer: Speed: Size: Part number: Serial number: Origin: Type: Manufacturer: Speed: Size: Part number: Serial number:	8192 MB SMBIOS DDR3 Elpida 1600 MHz 4096 MB EDJ8416E6MB-GN-F 78111110 SMBIOS DDR3 Micron 1600 MHz 4096 MB 8KTF51264HZ-166E1 12751016	
î‡:Up/Down Tab:Swit	ch Menu Enter:Select Esc:Baa	ck to home	Home 💧

Figure 35- System Information Screen – Memory Tab



System Information Screen with Motherboard tab selected is shown in Error! Reference source n

ot found.

Welcome, time 00:19	🛞 Len	ovo Diagnostics	Version 03.04.00
	<u>S</u> t	stem information:	
System System CFU Memory Display Storage CI-e	Number of USB host controllers Number of PCI RTC presence Resource Index Slot Class name Subclass name Resource Index Slot Class name Subclass name Resource Index Slot Class name Subclass name Subclass name Subclass name Subclass name Subclass name Subclass name Subclass name Subclass name	2 16 Yes PCI resource 1 0 Serial bus controller USB controller USB controller PCI resource 2 0 Bridge PCI bridge PCI bridge PCI resource 3 3 Network controller Network controller PCI resource 4 0 bisplay controller	
†↓:Up/Down Tab:Swit	ch Menu Enter:Select Esc:Back t	o home	Home

Figure 36 - System Information Screen – Motherboard Tab



System Information Screen with Optical Device tab selected is shown in Error! Reference source not f ound.

Lenovo diagnostics	System informati	Lon	
Machine CPU LCD Mem	ory Motherboard Or	otical Device	PCIe Storage -
OPTICAL DEVICE INFORMA	TION		
Manufacturer: Model number: Serial number: Firmware revision: Size: Sector size: Supported Features:	DVD-RAM UJ8DB SZD3K7494 8.01 OMB 0 Bytes	, DVD-RW RO, D	and the second of the second
Arrow	eys:navigation ESC	-back to home	
ALLOW	Version XX.XX.)		

Figure 37 - System Information Screen – Optical Device Tab



System Information Screen with PCI Express tab selected is shown in Error! Reference source not f ound..



Figure 38 - System Information Screen – PCI Express Tab



The System Information Screen with the Storage tab selected is shown in Error! Reference source n

ot found.

Welcome, time 00:19	(⊯ Le	enovo Diagnostics	Version 03.04.00
	-	System information:	
System System CPU Memory Display Motherboard Storage PCI-e	HIH/HIAPI 5: ATA/ATAPI 6: ATA/ATAPI 7: ATA8_ACS: Standard version: Model number: Manufacturer: Serial number: Firmware revision: Size: Rotation rate: Temperature: Physical sector size: Logical sector size:	HTS72505007E635 HGST RC055ACB0894RJ GS26B800 465 GB 7200 rpm 36 C 4096 bytes 512 bytes 976773168 sectors Supported Supported Supported Supported ATA8-ACS version 6 SSD SanDisk 142763405205 U21B001 14 GB Non-rotating media detected Not applicable 512 bytes 512 bytes 512 bytes	
†↓:Up/Down Tab:Swi	Physical sector size:	512 bytes 512 bytes 31277232 sectors	Home

Figure 39 - System Information Screen – Storage Tab

The System Information Screen is displayed after the user runs the option "System Information" on the Main Screen. The System Information Screen provides detailed information about the machine, the memory devices, and the storage devices. This screen is composed of:

- Application Title Bar;
- Screen Title Bar;
- Tab Names Bar;
- Tab Content Region;
- Instruction Bar

The Application Title Bar contains the name of the application;

The Screen Title Bar contains the name of the screen (in this case, System Information);



The Instruction Bar contains instructions to manage the screen;

The Tab Name Bar contains the name of all the available tabs and displays the tab currently selected (the name of current tab has a blue background to differentiate it from the other tabs);

The Tab Content Region contains information corresponding to tab currently selected;

User can change the current tab by pressing the Left and Right arrow keys. The Tab Content Region will display information about device on the current tab. User can also scroll information content using the Up and Down arrow keys if the number of content rows is greater than the number of rows on the screen.

For the **System tab**, the following information is displayed in the Tab Content Region:

- Machine Manufacturer;
- Product Name;
- Product Version;
- Serial Number;
- BIOS Revision;
- BIOS Release Date;
- BIOS Manufacturer;
- Processor Manufacturer;
- Processor Version.

For the <u>CPU tab</u>, the following information is displayed in the Tab Content Region:

- Model;
- Vendor;
- Number of cores;
- Number of threads;
- Signature;



- Max speed;
- Current speed;
- Features;
- Cache L1;
- Cache L2;
- Cache L3.

For the *Display tab*, the following information is displayed in the Tab Content Region:

- Manufacturer ID (a three-letter code identifying the manufacturer);
- Model Name;
- Date of Manufacture;
- EDID Version;
- Max resolution (in pixels);
- Max Image Size (in cm);
- Input Type (analog or digital); and
- Display Type.

For the *Fan tab*, the following information is displayed in the Tab Content Region:

- CPU fan speed;
- CPU temperature;

For the *Memory tab*, the following information is displayed in the Tab Content Region:

- Total Physical Memory (total of physical memory of machine in Gigabytes) and, for each memory device installed on machine:
- Identification of memory device (Origin);
- Type of memory (DDR2, DDR3, EEPROM and so on);
- Memory Manufacturer;



- Speed of memory (in MHz);
- Memory size (in Gigabytes);
- Memory Part Number;
- Memory Serial Number.

For the *Motherboard tab*, the following information is displayed in the Tab Content Region:

- Number of USB host controllers;
- Number of PCI;
- RTC presence;
- Resource:
- Index;
- Slot;
- Class name;
- Subclass name;

For the **Optical tab**, the following information is displayed in the Tab Content Region:

- Manufacturer;
- Model number;
- Serial number;
- Firmware revision;
- Size;
- Sector size;
- Supported features.

For the *PCI-e tab*, the following information is displayed in the Tab Content Region:



- Resource
- Bus (current item bus hexadecimal id);
- Device (current item device hexadecimal id);
- Function (current item function hexadecimal id);
- Device Connected (in case it's an external PCI Express off board connected)
- Vendor ID (current item vendor hexadecimal id)
- Class (current item class name)
- Subclass (current item subclass name)

For the **Storage tab**, the following information is displayed in the Tab Content Region:

- Model number
- Manufacturer;
- Serial Number;
- Firmware Revision;
- Size (in GB);
- Rotation rate;
- Temperature (in Celsius);
- Physical Sector Size (in bytes);
- Logical Sector Size (in bytes);
- Number of logical sectors;
- Supported Standards;
- ATA/ATAPI 4:
- ATA/ATAPI 5:
- ATA/ATAPI 6:
- ATA/ATAPI 7:
- Standard version;

UEFI – User Guide



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To exit the System Information Screen and go back to the Main Screen, the user must press the "ESC" key.

Recover Bad Sectors Tool Screen

Recover bad sectors is a tool that allows user to perform a test on system storages, identifying bad slots and allows user to recover these found bad blocks. When user selects this option on Man screen it displays two options to user.

- Check bad sector: this option makes a test on system storages and list the found bad blocks.
- Check and recover bad sector: this option makes a test on system storages list them to user and starts to correct the found bad blocks.

Welcome, time 08:32	Lenovo Diagnostics	Version 03.06.00
	Select Algorithm:	
	[]Check bad sectors []Check and recover bad sectors	
	Run Tests	
1↓:Up/Down Tab:Swite	ch Menu Space Bar:Check/Uncheck Enter:Select ESC:Back to home	Home

Figure 40 - Select Device Screen for Repair Bad Sectors Tool

When one of the options above are selected the application computes the number of storage devices installed on the system. If there is more than one storage device installed on the system, "Select Devices" is displayed.



The Select Device screen for the Repair Bad Sectors Tool is very similar to the Select Device Screen for Storage Device Test. One difference is that, for the Storage Device Test, the user can choose more than one device to be tested. For the Recover Bad Sectors Tool, the user can select only one device to be recovered.

Initially, only one device is selected. If the user selects another device, this device is selected and the device selected previously is deselected.

Another difference is that the Select Device screen for the Recover Bad Sectors Tools does not have a "Select/deselect all" option.

For the Recover Bad Sectors Tool, the user can only select one operation to be run.

Initially, only one operation is selected. If the user selects another operation, this operation is selected and the operation selected previously is deselected.

Another difference is that the Select Algorithm screen for the Recover Bad Sectors Tools does not have a "Select/deselect all" option.

Initially, the selected operation is "Check Bad Sectors". This operation checks all Storage Device's sectors looking for bad sectors. The other selectable operation is "Check and Recover Bad Sectors" (to check all sectors and recover found bad sectors).

IMPORTANT: The "Check and Recover Bad Sectors" operation performs write operations on a device, which may cause data loss. The user must make a backup of his data before running that operation.

If the user selects the "Check Bad Sectors" operation, a pop-up window will appear as shown in **Error! Reference source not found.**



Welcome, time 01:07		🛞 Lenovo Diagnostics	Version 03.04.00
		Tool Progress:	
Device 0: Size: Total sectors Testing secto Progress of (ors:	Alert: This test may take a long time to run. Do you want to continue? Press YES to confirm or NO to cancel. YES NO	2016/18/07 01:07:57 IN PROGRESS 0000/00/00 00:00:00
†↓:Up/Down Tab:S	witch Menu	Enter:Select Esc:Stop tests	Stop Tests

Figure 41 - Check Bad Sectors pop-up window

This pop-up window tells the user that this operation will take more than one hour to be finished and asks if the user wants to continue. To continue, the user must press the 'Y' key. If the user doesn't want to continue, the user must press the 'N' key.

If the user selects the "Check and Recover Bad Sectors" operation, a pop-up window will appear as shown in **Error! Reference source not found.**.

Page 71	3	– User Guide
Welcome, time 01:09	Henovo Diagnostics	Version 03.04.00
	Tool Progress:	
Device Size: files.	Alert: ntify and remap bad sectors, which might contain irretrievable d you must perform a backup to keep your existing data and operation rm or NO to cancel. YES NO	
†↓:Up/Down Tab:Switch Menu Ent	er:Select Esc:Stop tests	Stop Tests

UEFI – User Guide

Figure 42 - Check and Recover Bad Sectors pop-up window 1

This pop-up window warms user that this operation may cause data loss on Storage Device. To continue, user must press 'Y' key. After that, another pop-up window will appear as shown at Error! R eference source not found. User can also abort operation pressing 'N' key.



Henovo Diagnostics Welcome, time 01:10 Version 03.04.00 Tool Progress: Recover Bad Sector Infor Alert: Are you sure you want to continue with the Sector Recovery? Device 0: HGST -Press YES to confirm or NO to cancel. Size: 465 GB 2016/18/07 01:09:45 IN PROGRESS 0000/00/00 00:00:00 Total sectors: S Testing sectors: Progress of Operation YES NO ↑↓:Up/Down Tab:Switch Menu Enter:Select Esc:Stop tests Stop Tests

Figure 43 - Check and Recover Bad Sectors pop-up window 2

This pop-up window asks the user if the user really wants to continue this operation, due to the possibility of data loss. If the user wants to continue, the user must press the 'Y' key. If not, the user must press the 'N' key.

After all pop-up windows are closed, the Recover Bad Sectors Screen is displayed, as shown in **Error! Reference source not found.**.

clcome, time 01:12	🛞 Lenov	vo Diagnostics	Version 03.04.
		ol Progress:	
	168	RECOVER BAD SECTORS Started at: Check bad sectors Finished at: Status message:	Results 2016/18/07 01:12:47 IN PROGRESS 0000/00/00 00:00:00

UEFI – User Guide

Figure 44 - Recover Bad Sectors Tool Screen

The Recover Bad Sectors screen is very similar to the Quick Storage Device Test Screen, with a few differences.

In the Recover Results section, besides test start time, test end time, duration of Recover and instructions to user after operation is finished, additional information is shown.

For the Check Bad Sectors operation, the found bad sectors are displayed on the screen. For the Check and Recover Bad Sectors operation, the found bad sectors and result of their recovery (i.e. if bad sectors could be recovered or not) are displayed on the screen.

The Recover Result section can be scrolled up or down using the Up and Down arrow keys if the number of content rows for this section is greater than the number of rows on the screen.

During execution of the Recovery operation, the user can stop it at any time by pressing the ESC key. If the user does that, the operation is aborted. After the operation is finished or aborted, the user can go back to the Main Screen by pressing the 'ESC' key again or the user can see the Repair Log Screen by pressing the 'F3' key.

UEFI – User Guide



Exit Application

To exit the application, the user must select the option "Exit Application" on the Main Screen and press the ENTER key. Then, the interface will be closed and the machine will be reset.